

depositing ZnS thin films, such as; spin There are several methods for decomposition. In high purity thin films without They can easily be sublimed and resulting towards chemical and thermal treatment. the advantage of being sufficiently stable generally n-type semiconductors and have applications [6]. These materials are which may be of interest for the different possesses a specific number of defect states induced nonlinear optical effects[5], and it exceptioanally interesting for the photo- films materials. ZnS sintered film may be three molecule [2-4]. ZnS is

between molecules in comparison with the the weak Van der Waals interaction between molecular matter. The point is, that due to spectroscopy in application to thin film emphasizes the significance of thin film system [1-3]. Another important fact thin film optics to the mentioned molecular of the theoretical and experimental skills of properties naturally enforces the application of the gap window material and other photovoltaic devices. The analysis of the optical film suitable for solar cells, Wide band gap window material and other photovoltaic films may be clearly regarded as thin films materials. ZnS sintered film may be properties, X-ray diffraction.

1. Introduction:

Keywords: Zinc sulphide; spray pyrolysis; thin films; UV spectrophotometer; Optical properties; X-ray diffraction.

The article reports the preparation of ZnS films prepared by chemical method. The band gap of ZnS films is calculated theirs value are nearly of (4 eV) for all samples. The standard ASTM data at all annealing temperature used (450, 500, 550, 600 °C) of ZnS thin films. The grain size (D) increases with increasing temperature. The increase in the experiments the different angle θ and d - spacing values are in a well agreement with the thickness of annealing leads to lower peaks of x-ray diffraction pattern for structural analysis. The thickness of the prepared film is around (283 nm).

The article reports the preparation of ZnS films prepared by spray pyrolysis. The increase in the temperature of annealing leads to lower peaks of x-ray diffraction pattern for structural analysis. The thickness of the prepared film is around (283 nm).

Abstract:

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Preparation and study optical transparency of spray deposited ZnS films with different annealing temperatures

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